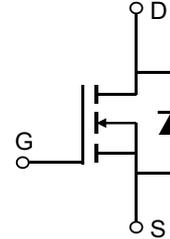


Description

Features

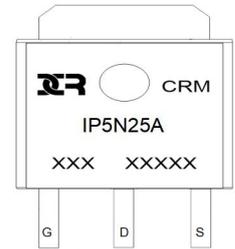
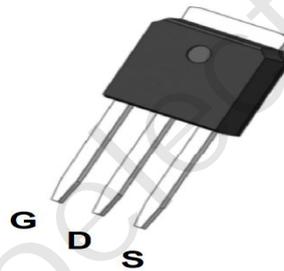
- 250V, 5A
 $R_{DS(ON)}$ Typ = 468mΩ @ $V_{GS} = 10V$
 Advanced Trench Technology
- Excellent $R_{DS(ON)}$ and Low Gate Charge
- 100% UIS TESTED!
- 100% ΔV_{ds} TESTED!



Schematic Diagram

Application

- Load Switch
- PWM Application
- Power Management



Marking and Pin Assignment

Package Marking and Ordering Information

Device	Marking	Package	Outline	TUBE(pcs)	Inner Box (pcs)	Per Carton (pcs)
CRMIP5N25A	CRMIP5N25A	TO-251-3L	TUBE	72	4320	21600

Absolute Maximum Ratings (@ $T_j = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Units
V_{DS}	Drain-to-Source Voltage	250	V
V_{GS}	Gate-to-Source Voltage	±30	V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	5
		$T_C = 100^\circ\text{C}$	3
I_{DM}	Pulsed Drain Current ⁽¹⁾	20	A
E_{AS}	Single Pulsed Avalanche Energy ⁽²⁾	120	mJ
P_D	Power Dissipation	$T_C = 25^\circ\text{C}$	31.25
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4	°C/W
T_J, T_{STG}	Junction & Storage Temperature Range	-55 to 150	°C

Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	I _D = 250μA, V _{GS} = 0V	250	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250V, V _{GS} = 0V	-	-	1.0	μA
I _{GSS}	Gate-Body Leakage Current	V _{DS} = 0V, V _{GS} = ±30V	-	-	±100	nA
On Characteristics						
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.5	3	3.5	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽³⁾	V _{GS} = 10V, I _D = 2.5A	-	468	562	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance		-	465	-	pF
C _{oss}	Output Capacitance	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz	-	68	-	pF
C _{rss}	Reverse Transfer Capacitance		-	10	-	pF
Q _g	Total Gate Charge		-	10	-	nC
Q _{gs}	Gate Source Charge	V _{GS} = 0 to 10V	-	3	-	nC
Q _{gd}	Gate Drain("Miller") Charge	V _{DS} = 200V, I _D = 5A	-	5.2	-	nC
Switching Characteristics						
t _{d(on)}	Turn-On DelayTime		-	6	-	ns
t _r	Turn-On Rise Time	V _{GS} = 10V, V _{DD} = 150V	-	25	-	ns
t _{d(off)}	Turn-Off DelayTime	I _D = 5A, R _{GEN} = 25Ω	-	22	-	ns
t _f	Turn-Off Fall Time		-	24	-	ns
Drain-Source Diode Characteristics and Max Ratings						
I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	5	A
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	20	A
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _S = 2.5A	-	-	1.2	V
t _{rr}	Body Diode Reverse Recovery Time		-	423	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F = 5A, di/dt = 100A/us	-	4.3	-	nC

- Notes:
1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
 2. E_{AS} condition: Starting T_J=25°C, V_{DD}=100V, V_G=10V, R_G=25ohm, L=10mH, I_{AS}=4.9A
 3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 0.5%.

Test Circuit

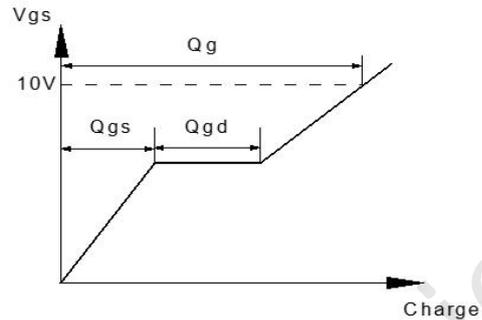
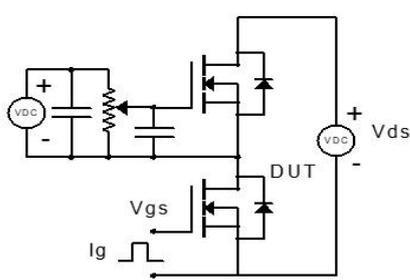


Figure 1: Gate Charge Test Circuit & Waveform

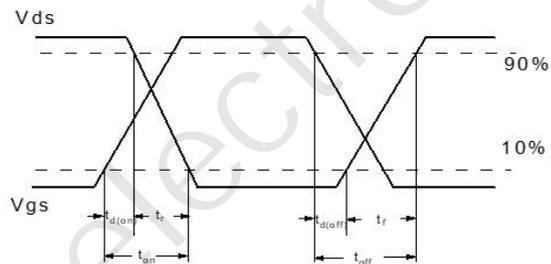
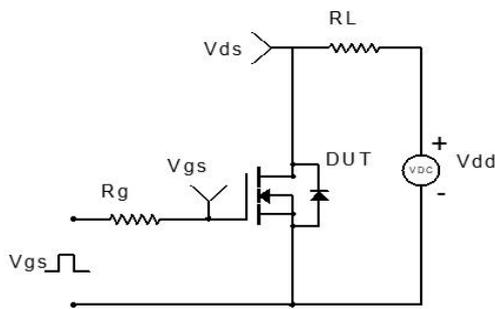


Figure 2: Resistive Switching Test Circuit & Waveform

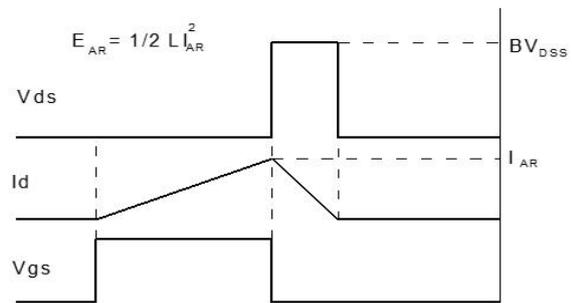
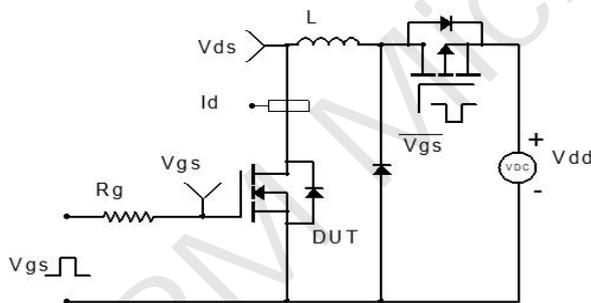


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

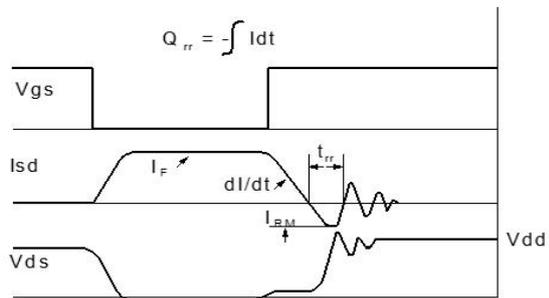
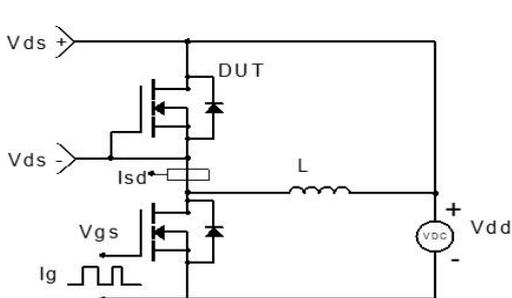
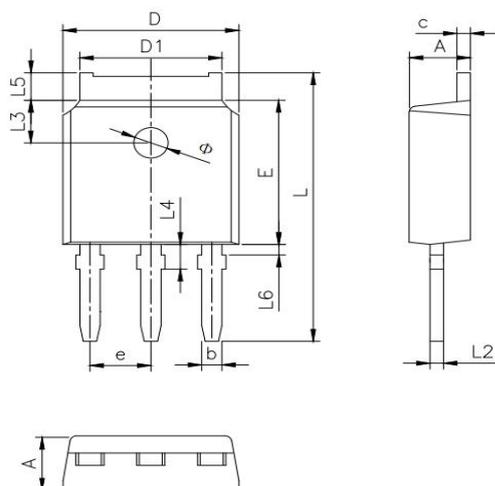


Figure 4: Diode Recovery Test Circuit & Waveform

Package Mechanical Data(TO-251-3L)



SYMBOL	MILLIMETER		
	MIN	NOM	MAX
A	2.20	2.30	2.40
b	0.66	0.76	0.86
c	0.46	0.51	0.58
D	6.50	6.60	6.70
D1	5.10	5.33	5.46
D2	4.83 REF.		
E	6.00	6.10	6.20
e	2.19	2.29	2.39
L	11.02	11.22	11.42
L1	4.10 REF.		
L2	0.508BSC		
L3	1.80 REF.		
L4	0.95	1.05	1.15
L5	0.90	--	1.25
L6	0.15	--	0.75
Φ	1.10	--	1.30
V	5.40 REF.		

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